

Apprentissage Artificiel (Statistical Machine-Learning)

General framework + Supervised Learning

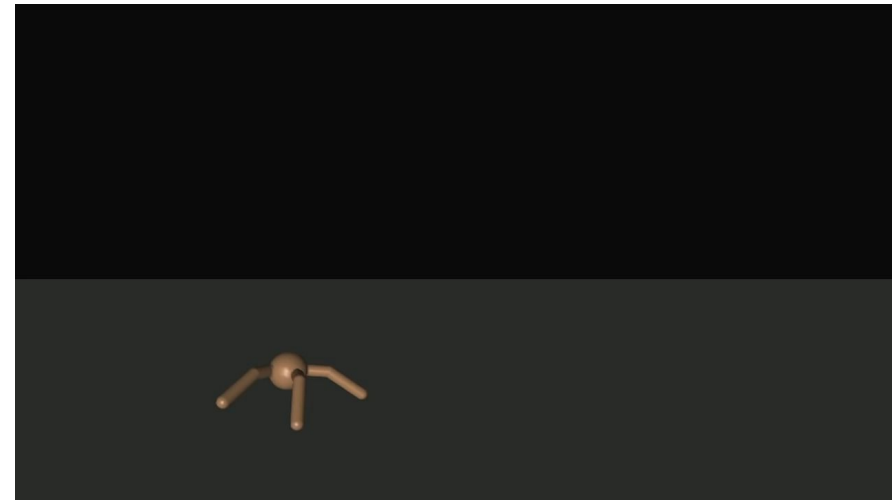
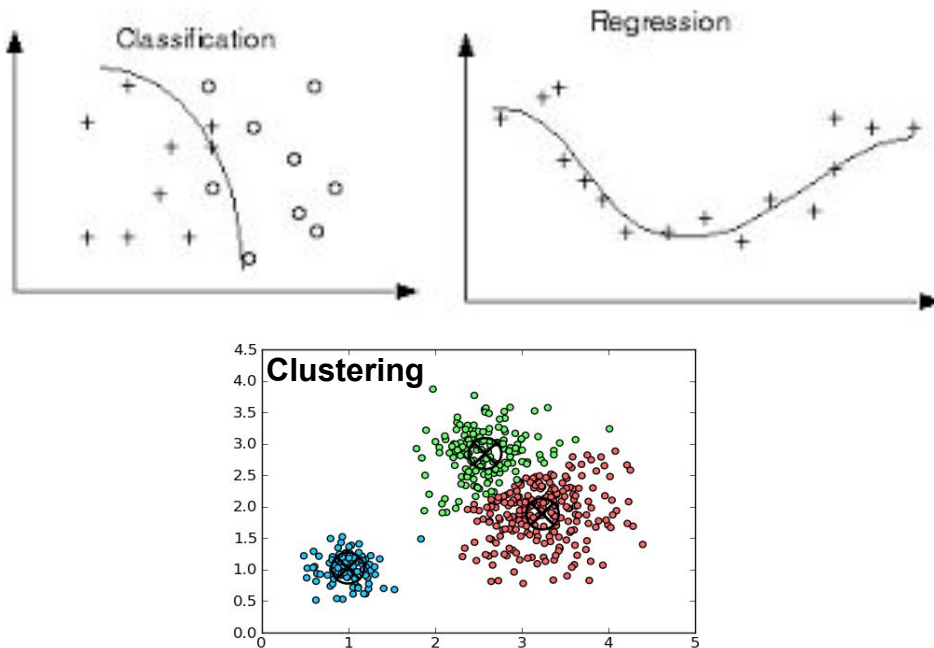
Assoc. Prof. Sascha Hornauer

Center for Robotics
Mines Paris
PSL Université

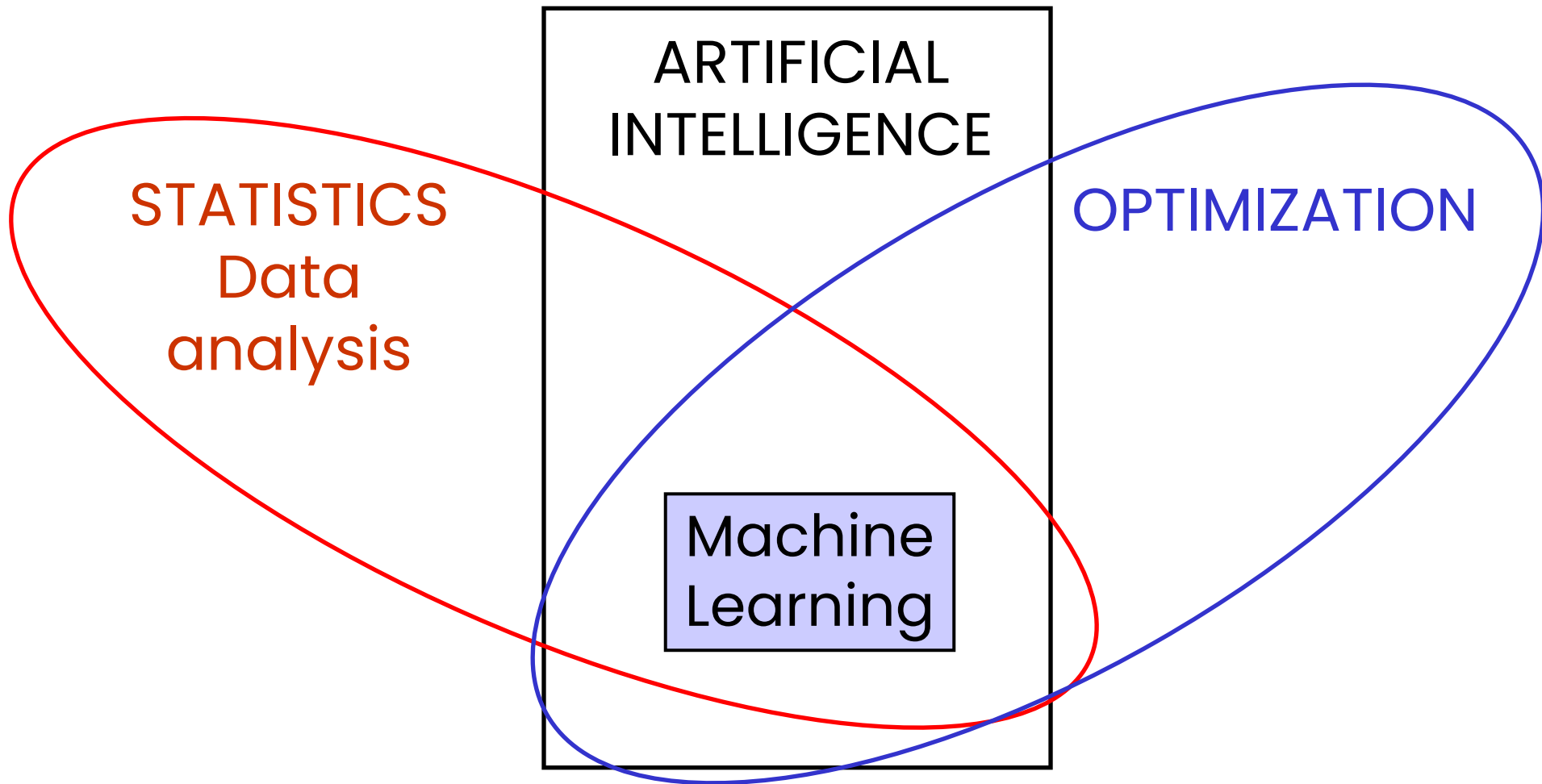
sascha.hornauer@minesparis.psl.eu

- Intro: What is Statistical Machine-Learning?
- Typology of Machine-Learning
- General formalism for SUPERVISED Learning
- Evaluating learnt models:
metrics for CLASSIFICATION
- Generalization vs. overfitting

- One of many sub-fields of Artificial Intelligence
- Application of optimization methods to statistical modelling
- Data-driven mathematical modelling, for automated *classification, regression, partitioning/clustering*, or *decision/behavior rule*

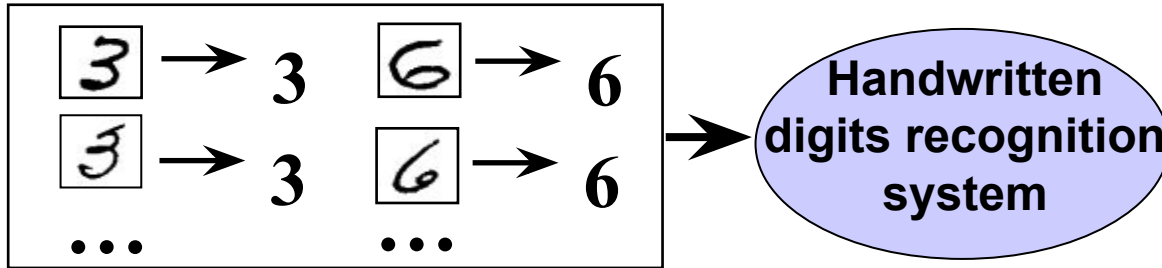


What is Statistical Machine-Learning?



Real-world examples of Machine-Learning applications

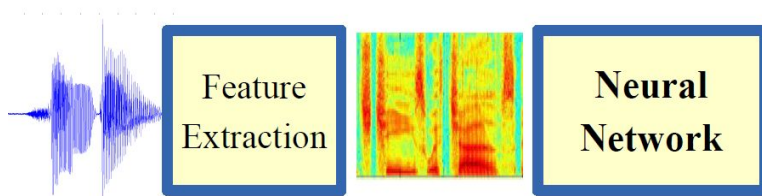
- Handwritten characters recognition



- Object category visual recognition

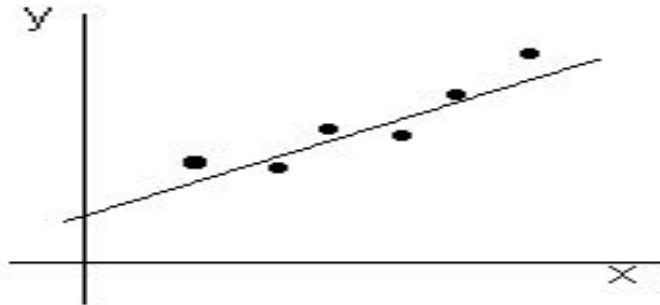


- Speech recognition



- Multi-factorial forecasting
- Natural Language understanding
- Playing GO!
- MANY MANY MORE...

One of simplest ML algorithm: Least Squares Linear Regression



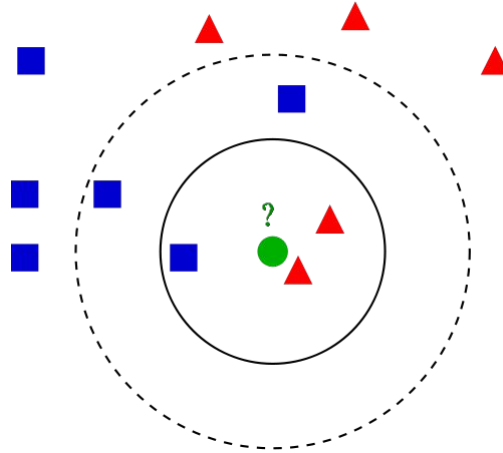
- **Model:** (straight) line $y=ax+b$ (2 parameters a and b)
- **Data:** n points with target value $(x_i, y_i) \in \mathbb{R}^2$
- **Cost function:** sum of squares of deviation from line

$$K = \sum_i (y_i - a \cdot x_i - b)^2$$

- **Algorithm:** direct (or iterative) solving of linear system

$$\begin{pmatrix} \sum_{i=1}^n x_i^2 & \sum_{i=1}^n x_i \\ \sum_{i=1}^n x_i & n \end{pmatrix} \cdot \begin{pmatrix} a \\ b \end{pmatrix} = \begin{pmatrix} \sum_{i=1}^n x_i y_i \\ \sum_{i=1}^n y_i \end{pmatrix}$$

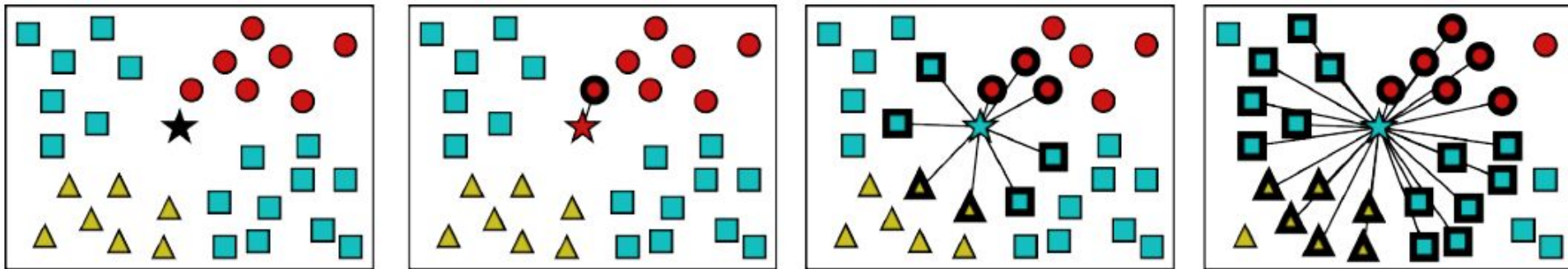
Simplest *classification* method: Nearest Neighbors algorithm



Principle of Nearest Neighbors (kNN) for classification

[What are the main drawbacks of this method??]

k-Nearest Neighbors



- Some outlier vectors get 'outvoted' with high enough number **k** of neighbors

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Supervised vs Unsupervised learning

Learning is called "supervised" when there are "target" values for every example in training dataset:

examples = (input , output) = (\mathbf{x}_1, y_1) , (\mathbf{x}_2, y_2) , ... , (\mathbf{x}_n, y_n)

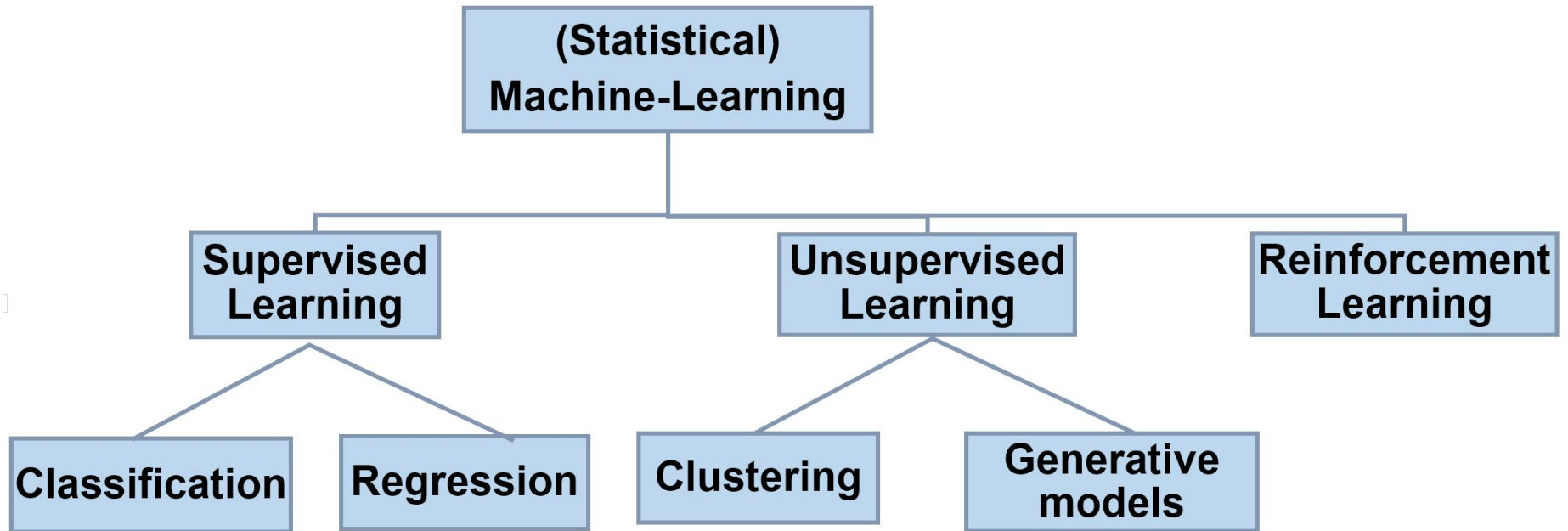
The goal is to build a (generally non-linear) approximate model for interpolation, in order to be able to **GENERALIZE** to input values other than those in training set

"Unsupervised" = when there are NO target values:

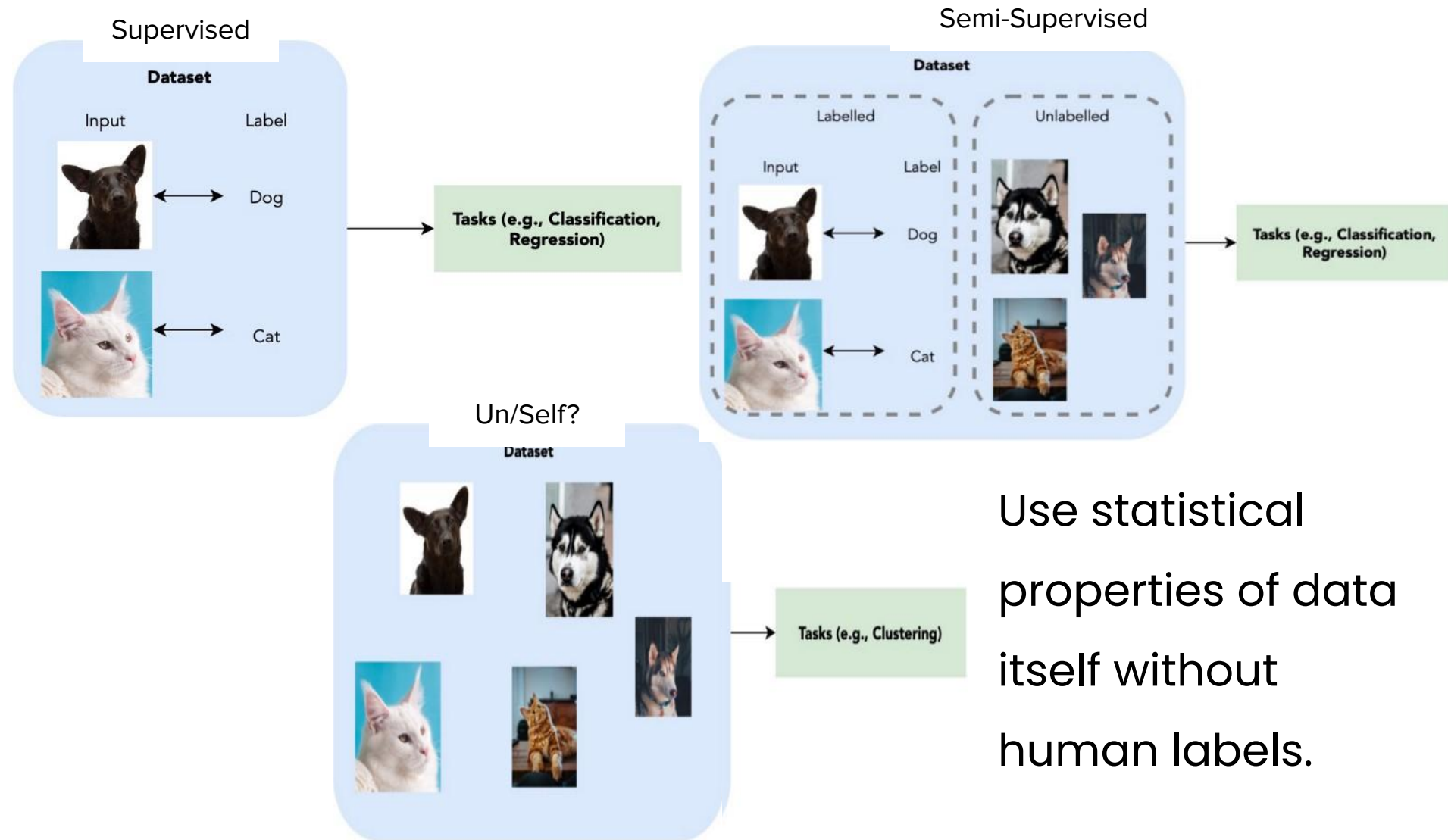
dataset = $\{\mathbf{x}_1, \mathbf{x}_2, \dots, \mathbf{x}_n\}$

The goal is typically either to do datamining (unveil structure in the distribution of examples in input space)

- **Availability of target output data?**
 - Supervised learning vs. Unsupervised learning
or *Reinforcement Learning*
- **Permanent adaptability?**
 - offline learning vs. online (life-long) learning
- **What kind of (mathematical) model?**
 - polynom/spline, decision tree, neural net, kernel machine, ...
- **Which objective function?**
 - cost function (quadratic error, ...), implicit criterium, ...
- **How to find the best-fitting model?**
 - algorithm type (exact solving, gradient descent, quadratic optimization, heuristics, ...)

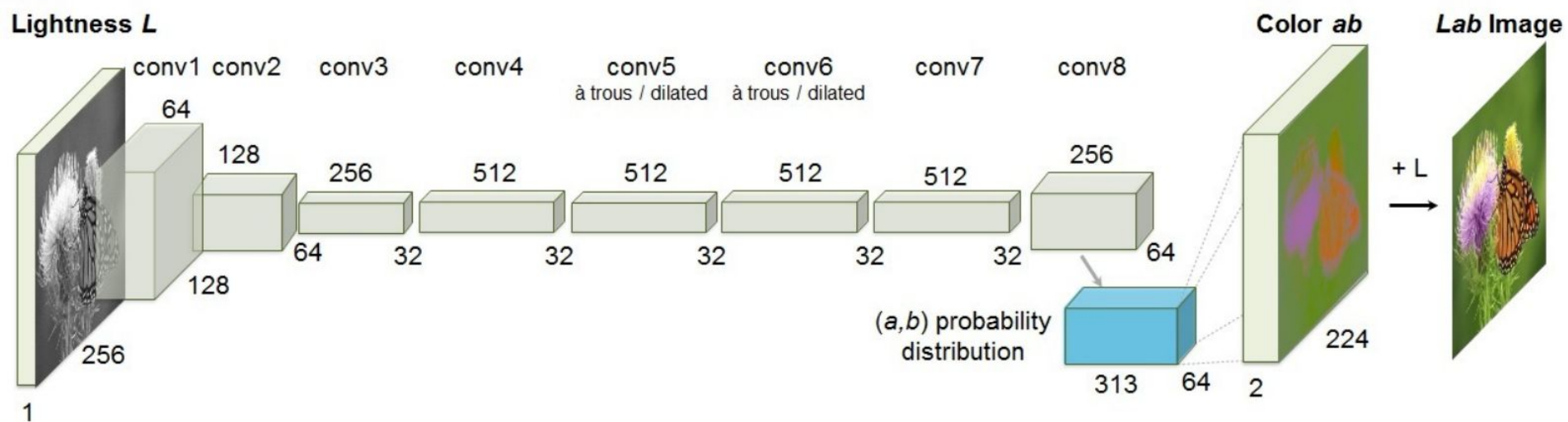


Un- or Self-Supervised Training?



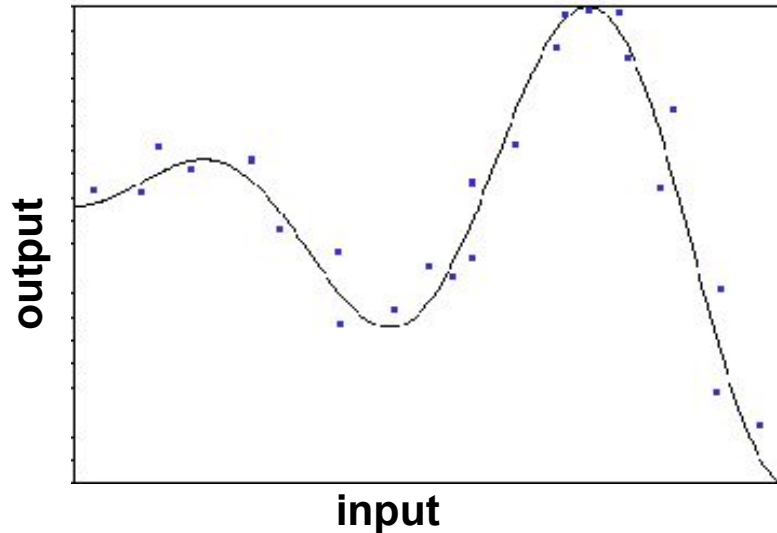
Images: <https://towardsdatascience.com/supervised-semi-supervised-unsupervised-and-self-supervised-learning-7fa79aa9247c>

Self-Supervised Learning



SUPERVISED LEARNING: regression or classification

Regression

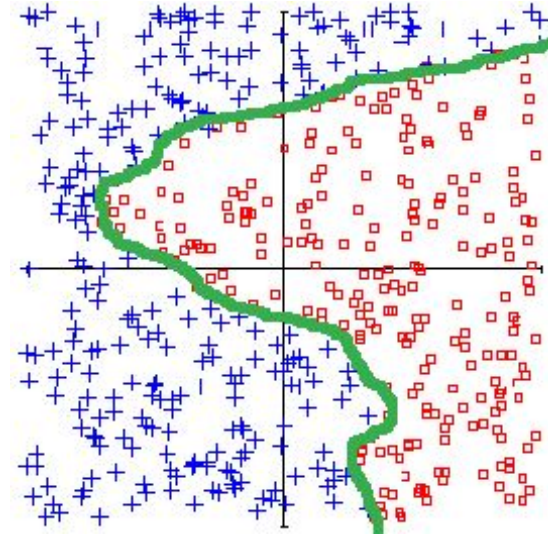


*Examples $\{(x_i, y_i), i=1, \dots, N\}$
 $x_i = \text{input}$, $y_i = \text{target output}$*

□ *Infer: curve = regression $y \approx h(x)$*

y: Continuous output(s)

Classification

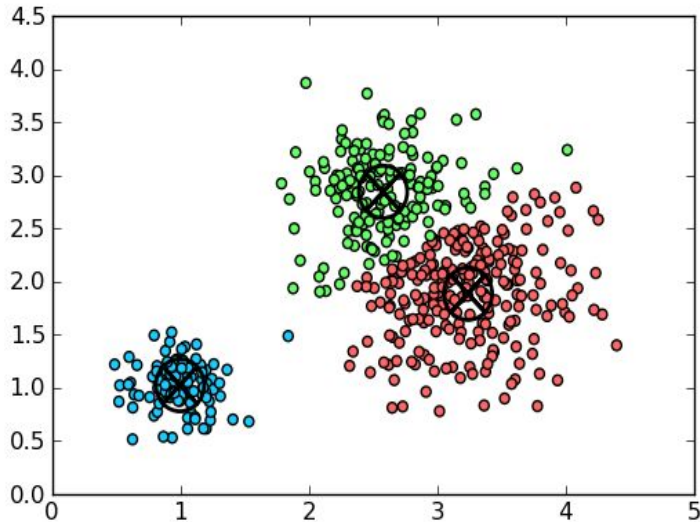


*Input $\{x_i, i=1, \dots, N\}$ = points positions
 target Output = class label ($\square = -1, + = +1$)*

□ *Infer: label = $h(x)$
 (and separation boundary)*

y: Discrete output(s)

Clustering



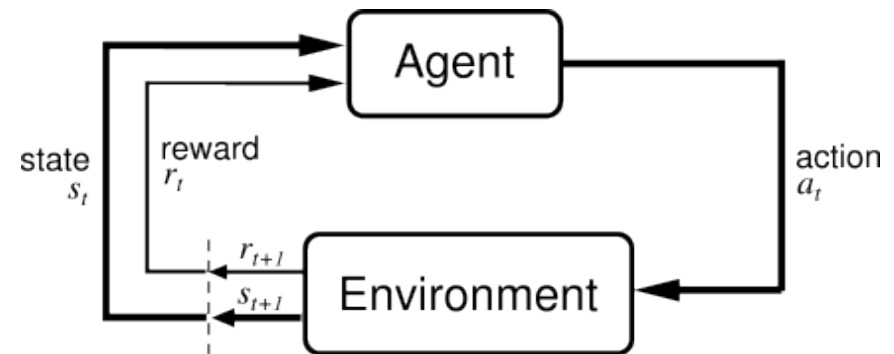
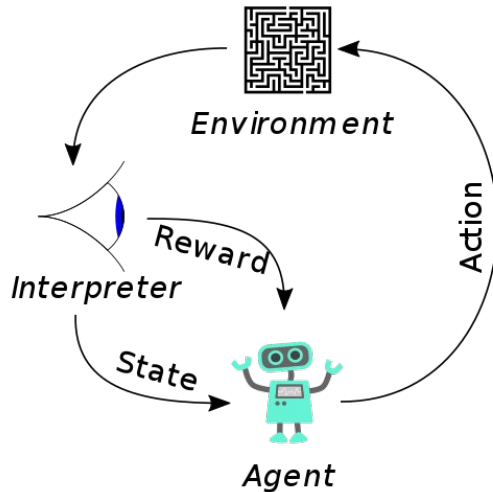
Points = examples

- ☐ **partitioning in “groups” (colors)
based on similarity**

Generative model

***From examples x_n , estimate the
PROBABILITY DISTRIBUTION $p(x)$***

- ☐ ***Can GENERATE new examples
SIMILAR to those in training set***



Goal: find a “policy” $a_t = \pi(s_t)$ that

maximizes
$$R_t = \sum_{k=0}^{\infty} \gamma^k r_{t+k}, \gamma \in [0, 1[$$

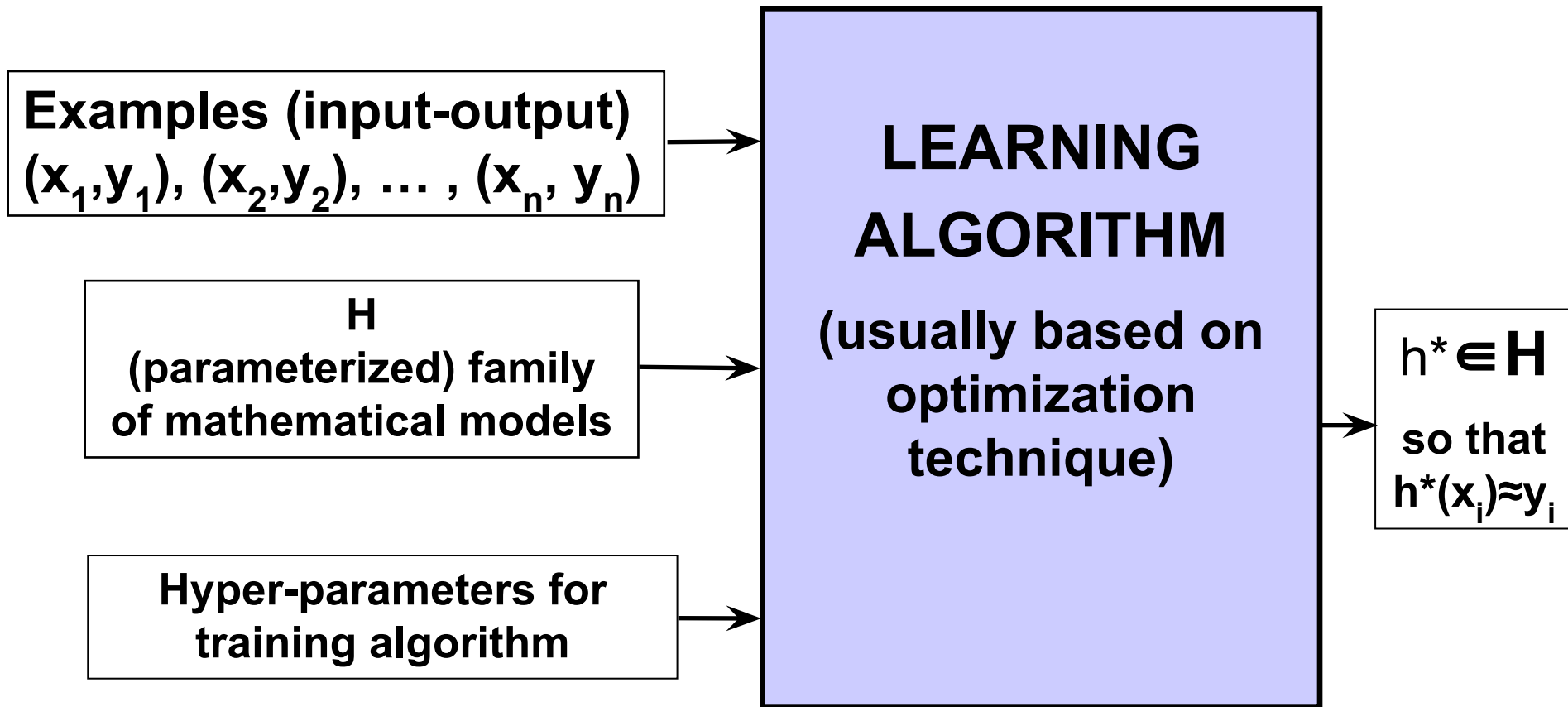
Typical use of RL: learn a BEHAVIOR

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Many different supervised ML approaches & algorithms

- Linear regressions
- Decision trees (ID3 or CART algorithms)
- Bayesian (probabilistic) methods
- ...
- Multi-layer neural networks trained with gradient backpropagation
- Support Vector Machines
- Boosting of "weak" classifiers
- Random forests
- Deep Learning (Convolutional Neural Networks,...)
- ...

Supervised learning



In most cases, $h^* = \arg\min_{h \in H} K(h, \{(x_i, y_i)\})$ where $K = \text{cost}$
 $K = \sum_i \text{loss}(h(x_i), y_i) [+ \text{regularization-term}]$ and $\text{loss} = \|h(x_i) - y_i\|^2$

Cost function and loss function

Most *supervised* Machine-Learning algorithms work by minimizing a "cost function"

- The cost function is generally the average over all training examples of a "loss function"

$$K = \sum_i \text{loss}(h(x_i), y_i)$$

(+ sometimes an additional « *regularization* » term)

- The *loss function* is usually some measure of the difference between target value and prediction by the output of the learnt model

Linear Regression, Mean Square Loss:

- decision rule: $y = W'X$
- loss function: $L(W, y^i, X^i) = \frac{1}{2}(y^i - W'X^i)^2$
- gradient of loss: $\frac{\partial L(W, y^i, X^i)}{\partial W} = -(y^i - W(t)'X^i)X^i$
- update rule: $W(t+1) = W(t) + \eta(t)(y^i - W(t)'X^i)X^i$
- direct solution: solve linear system $[\sum_{i=1}^P X^i X^{i'}]W = \sum_{i=1}^P y^i X^i$

[From slide by Y. LeCun: Machine Learning and Pattern Recognition]

Logistic Multivariate Regression

If target output is binary (classification)

Logistic Regression, Negative Log-Likelihood Loss function:

■ decision rule: $y = F(W'X)$, with $F(a) = \tanh(a) = \frac{1 - \exp(a)}{1 + \exp(a)}$

Or Sigmoid

■ loss function: $L(W, y^i, X^i) = 2 \log(1 + \exp(-y^i W' X^i))$

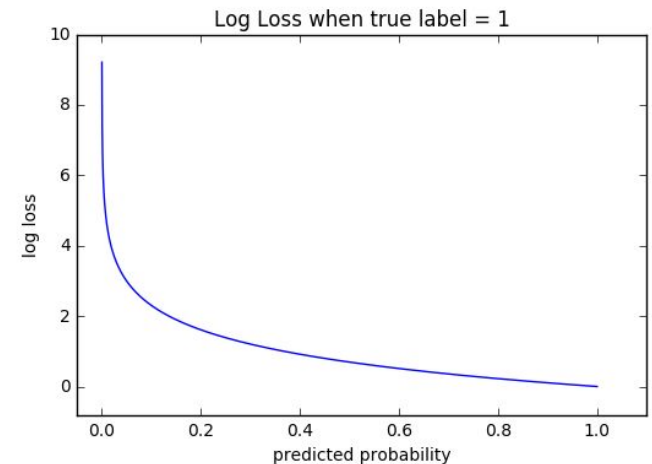
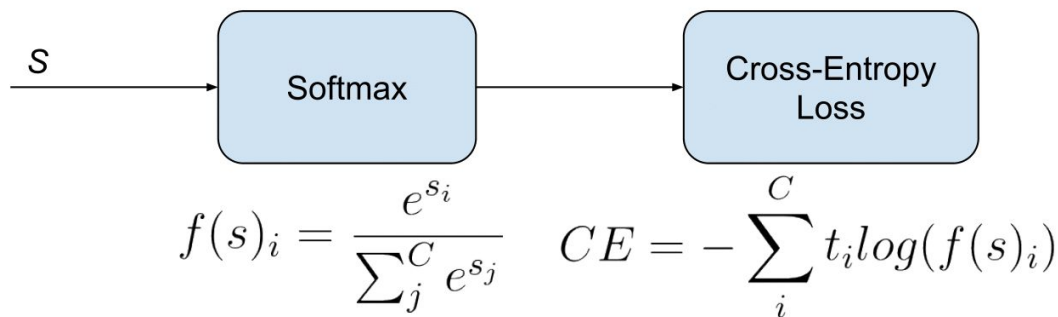
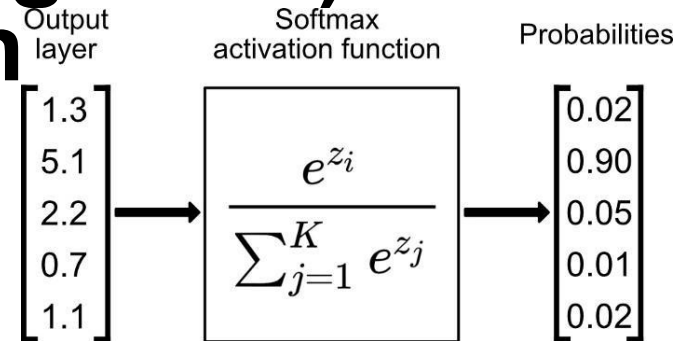
■ gradient of loss: $\frac{\partial L(W, y^i, X^i)}{\partial W} = -(Y^i - F(W' X)) X^i$

■ update rule: $W(t+1) = W(t) + \eta(t)(y^i - F(W(t)' X^i)) X^i$

[From slide by Y. LeCun: Machine Learning and Pattern Recognition]

Cross Entropy Loss (Log Loss) for Classification

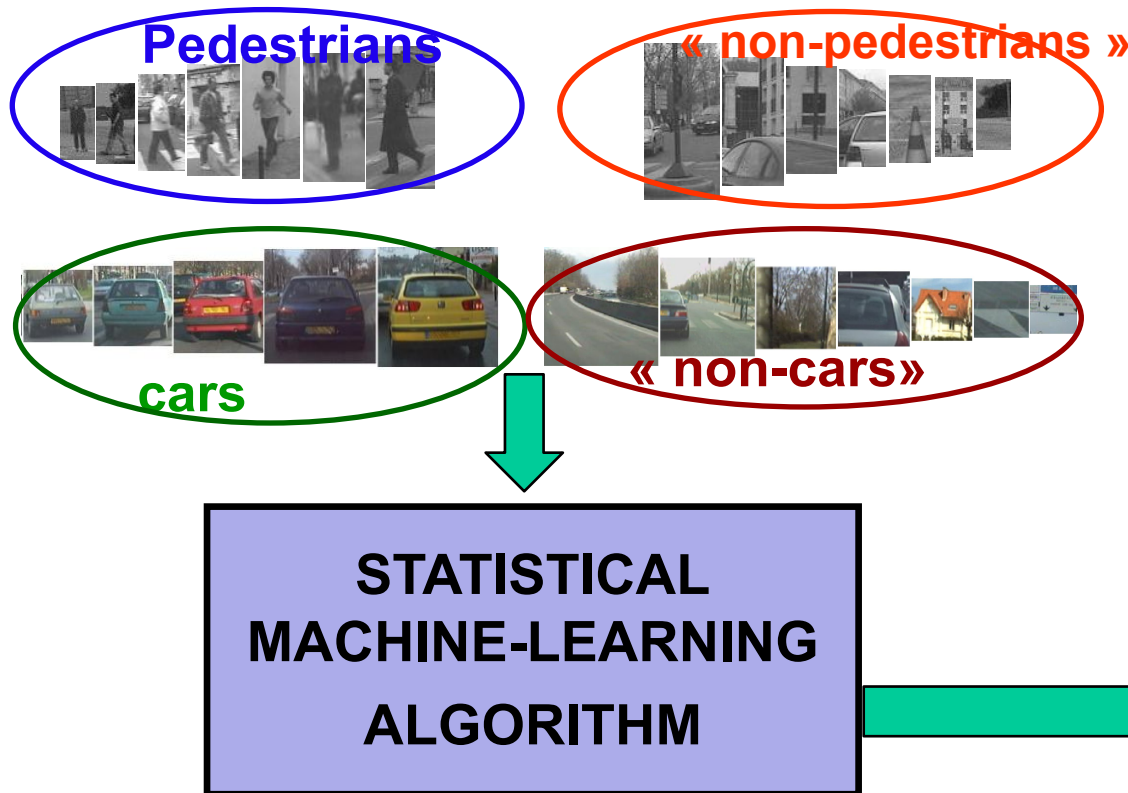
- **If** true label 1: Prediction lower than 0.5 is **confident and wrong** answer
→ penalize heavily



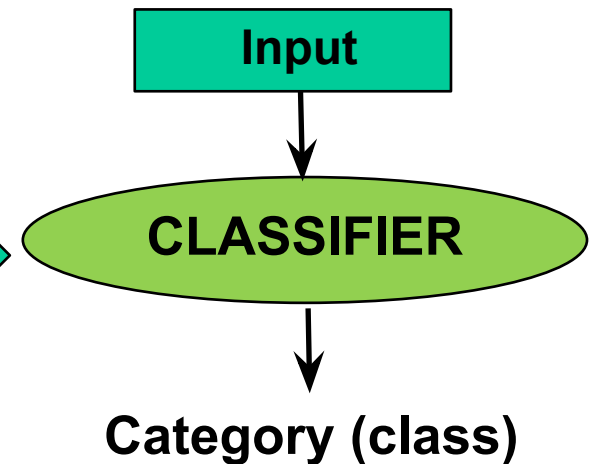
Compare: https://ml-cheatsheet.readthedocs.io/en/latest/loss_functions.html

Usual two distinct phases of supervised Machine-Learning

Training

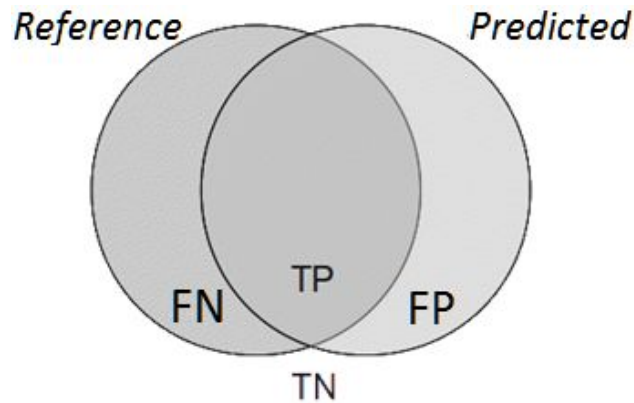


Recognition



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Different types of classification errors

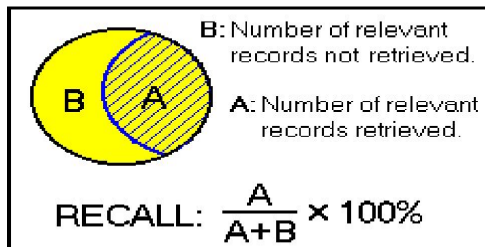


	predicted as positive	predicted as negative
positive	TP	FN
negative	FP	TN

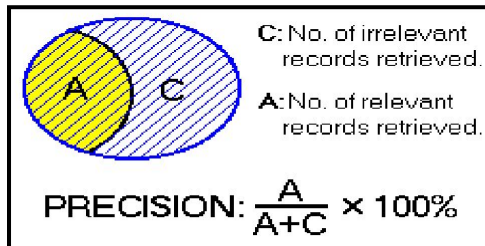
Error rate =

$$(FP + FN) / (TP + TN + FP + FN)$$

BUT: False Negatives ("missed") \neq False Positives!



Recall: percentage of relevant examples successfully predicted/retrieved



Precision: percentage of actually relevant examples among all those returned by the classifier

Accuracy, recall & precision formulas

	predicted as positive	predicted as negative
positive	TP	FN
negative	FP	TN

Accuracy
("correctness")
[en français, exactitude]

$$= \frac{\# \text{ of } \underline{\text{correct}} \text{ predictions}}{\text{Total } \# \text{ of examples}} = \frac{TP + TN}{TP + TN + FP + FN}$$

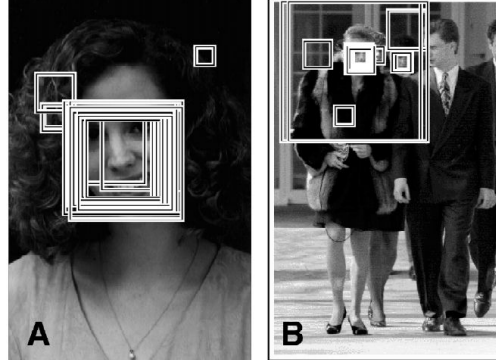
Recall
(sensitivity)
True Positive rate

$$= \frac{\# \text{ of } \underline{\text{correct}} \text{ } \underline{\text{positive}} \text{ predictions}}{\# \text{ of } \underline{\text{real}} \text{ positives}} = \frac{TP}{TP + FN}$$

Precision
(specificity)

$$= \frac{\# \text{ of } \underline{\text{correct}} \text{ } \underline{\text{positive}} \text{ predictions}}{\# \text{ of positive } \underline{\text{predictions}}}} = \frac{TP}{TP + FP}$$

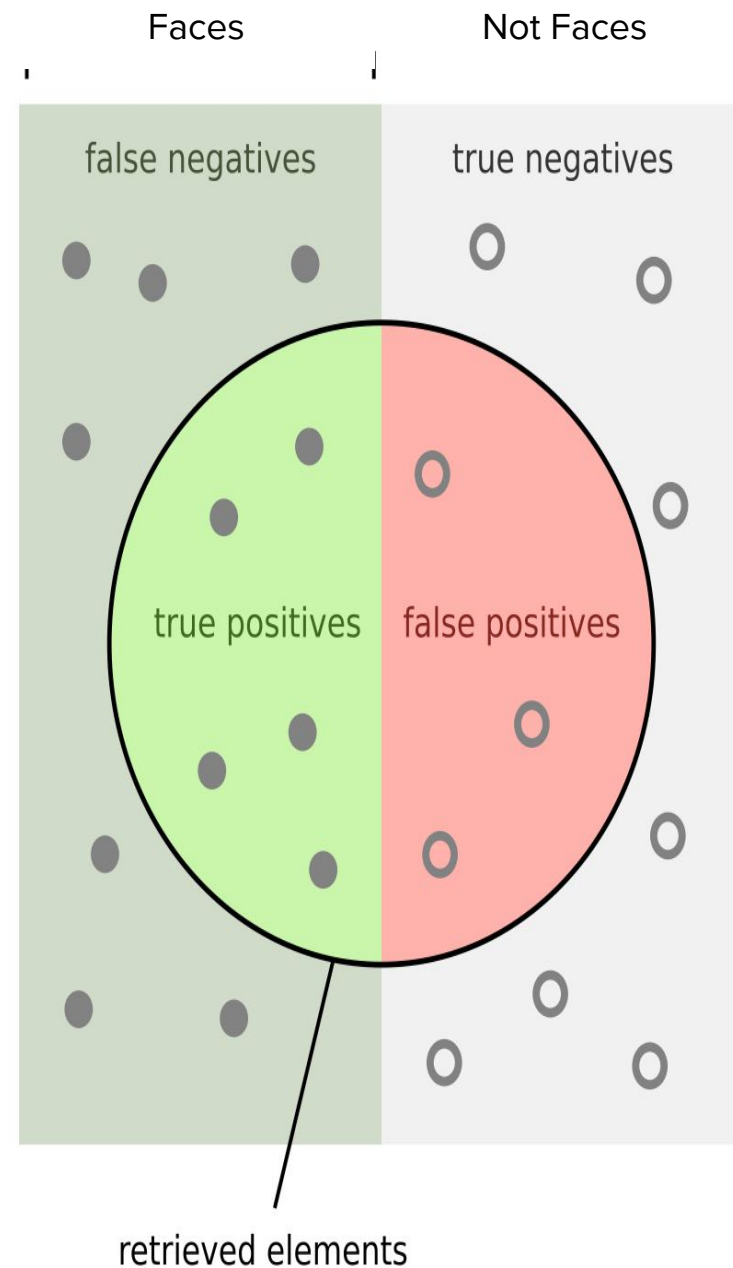
Precision



$$\text{Precision} = \frac{\text{True Positives}}{\text{True Positives} + \text{False Positives}}$$

How many retrieved boxes show faces?

$$\text{Precision} = \frac{\text{True Positives}}{\text{True Positives} + \text{False Positives}}$$

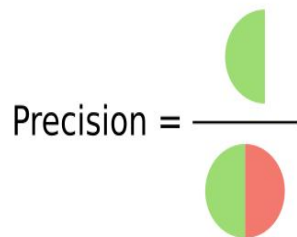


Precision, Recall

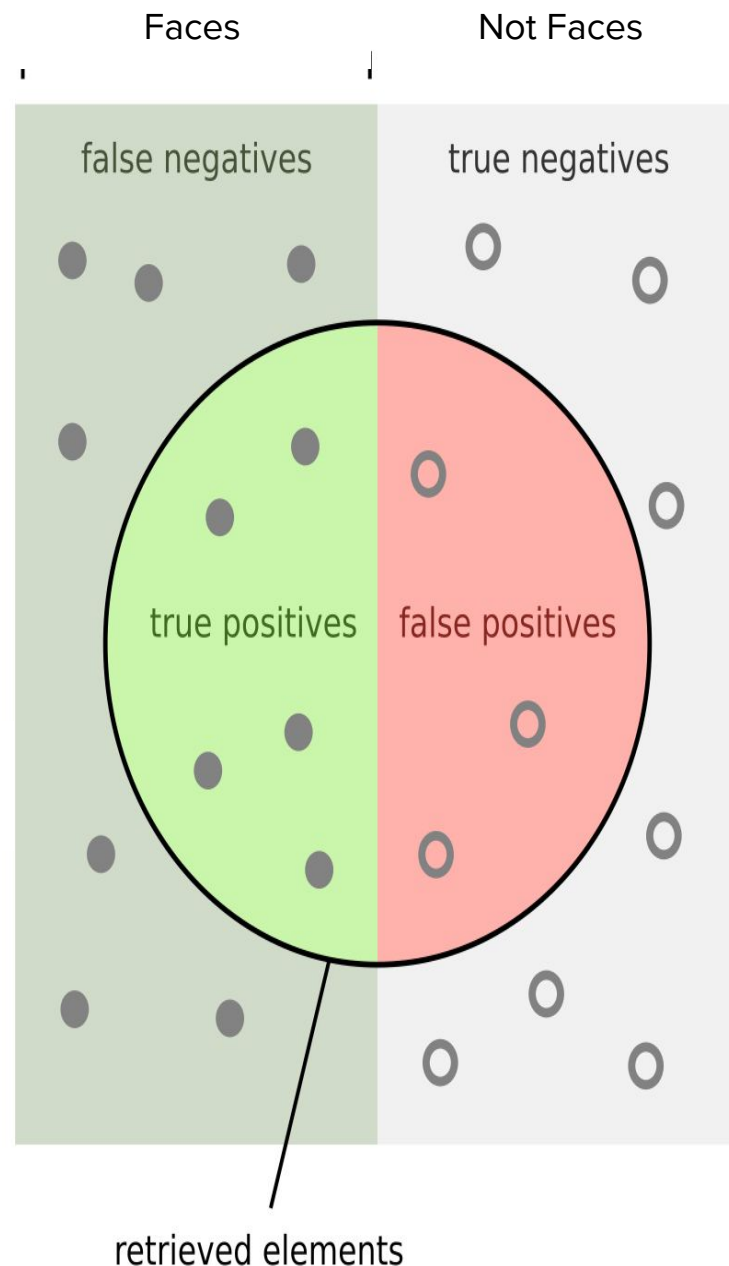
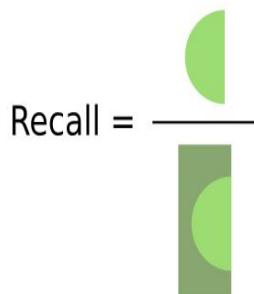
$$\text{Precision} = \frac{\text{True Positives}}{\text{True Positives} + \text{False Positives}}$$

$$\text{Recall} = \frac{\text{True Positives}}{\text{True Positives} + \text{False Negatives}}$$

How many retrieved boxes
show faces?



How many faces
are retrieved?



F1 - Score

- Single metric of 'harmonic mean'
- Mostly used to compare classification results
- Precision and Recall usually inversely related

$$F_1 = 2 \cdot \frac{Precision \cdot Recall}{Precision + Recall}$$

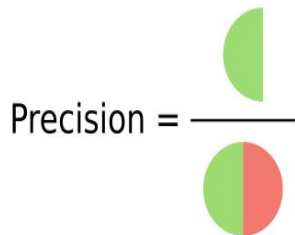
Case: High Precision, Low Recall

All boxes contain faces but did not find a lot ->
Classifier too careful, underestimating count of faces

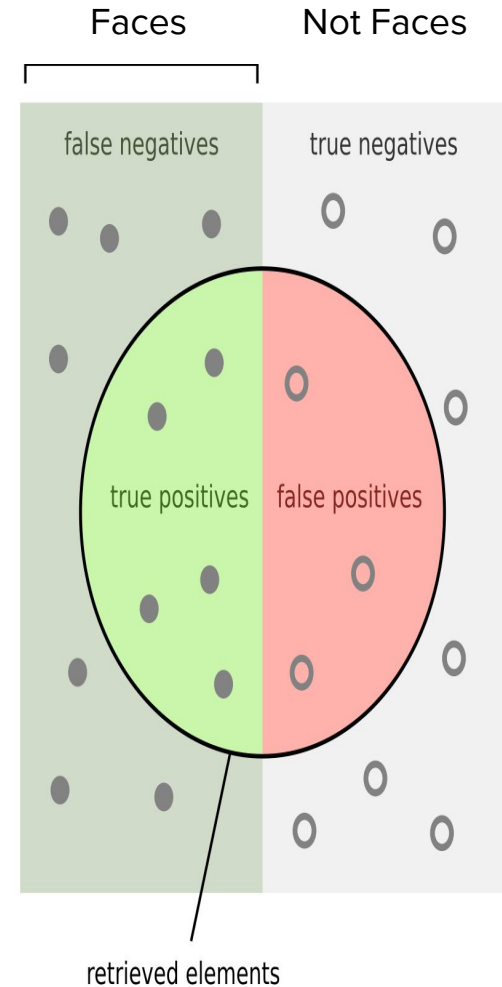
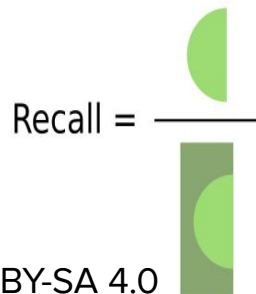
F1 Score -> Numerator goes down due to low recall

$$F_1 = 2 \cdot \frac{Precision \cdot Recall}{Precision + Recall}$$

How many retrieved boxes
show faces?



How many faces
are retrieved?



Other Case: Low Precision, High Recall

High Recall: No false negatives -> All faces were found

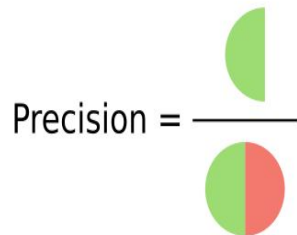
Low Precision: Also, many false positives

Classifier sees faces everywhere

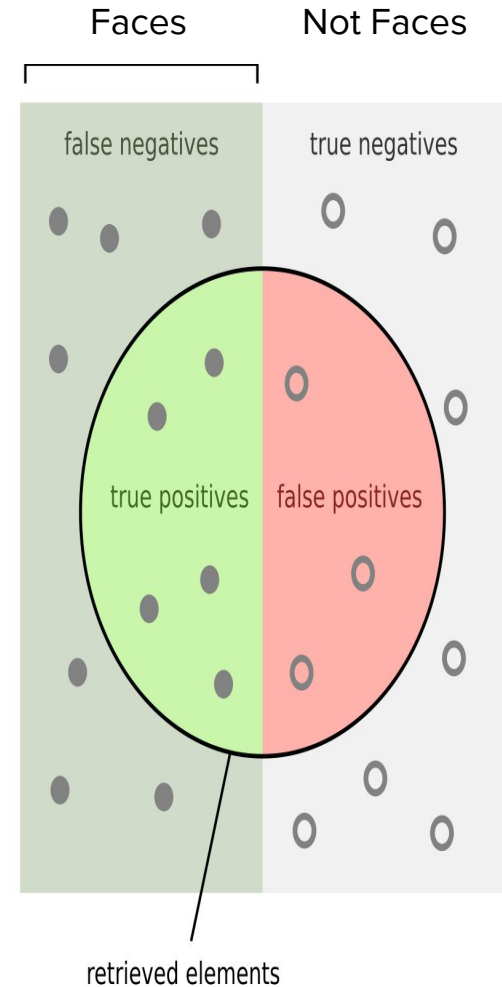
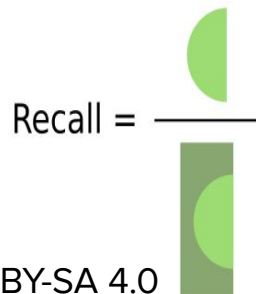
F1 Score -> Numerator goes down due to low precision

$$F_1 = 2 \cdot \frac{\textit{Precision} \cdot \textit{Recall}}{\textit{Precision} + \textit{Recall}}$$

How many retrieved boxes show faces?



How many faces are retrieved?

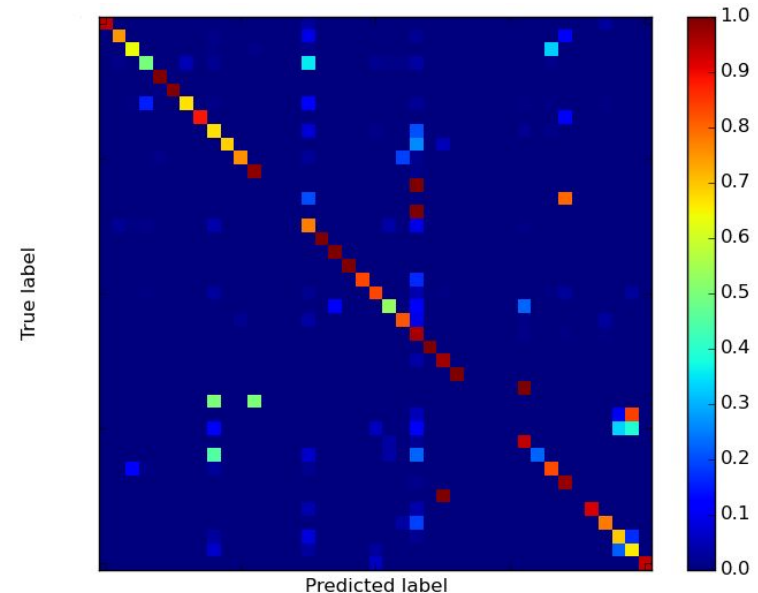


Classification performance metrics

- **Accuracy** = proportion of correct
- **Recall (sensitivity)** \approx proportion of "not missed"
 \approx "completeness" level [*exhaustivité*]
- **Precision (specificity)** \approx *reliability* of predicted labels
- **Confusion matrix**: predicted label v.s. true label

True positive	False positive
True negative	False negative

C.Matrix	1	2	3	4	5	6	ACTUAL	RECALL
1	339	15	5	0	0	0	359	94.43%
2	15	305	14	0	0	0	334	91.32%
3	6	10	242	0	0	0	258	93.80%
4	0	0	0	302	30	0	332	90.96%
5	0	0	0	15	368	0	383	96.08%
6	0	0	0	0	0	394	394	100.00%
PREDICTED	360	330	261	317	398	394	2060	94.43%
PRECISION	94.17%	92.42%	92.72%	95.27%	92.46%	100.00%	94.51%	94.66%

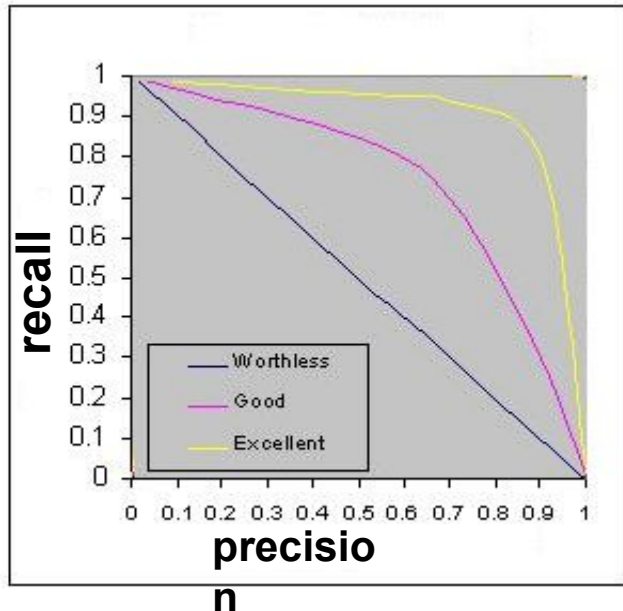


Precision-recall trade-off and curve

Classifier C1 predicts better than C2

iff C1 has better recall and precision

+ Trade-off between recall and precision



□ Compare precision-recall curves!

For numeric comparison (or if curves cross each other),
Area Under Curve (AUC)

Quality measures of learnt model: loss function and error types

- Quality measure for a learnt model h :

$$Q(h) = E(L(h(x), y))$$

where $L(h(x), y)$ is the « *LOSS function* »

$$\text{often} = \|h(x) - y\|^2$$

- What optimum for h ?

h^* *absolute* optimum = $\text{argMin}_h (E(h))$

h^*_H optimum *within H family* = $\text{argMin}_{h \in H} (E(h))$

$h^*_{H,n}$ optimum *in H from finite set of examples* =
 $\text{argMin}_{h \in H} (E_n(h))$

where $E_n(h) = (1/N) \sum_i (L(h(x_i), y_i))$

$$E(h^*_{H,n}) - E(h^*) = \underbrace{[E(h^*_{H,n}) - E(h^*_H)]}_{\text{ESTIMATION error}} + \underbrace{[E(h^*_H) - E(h^*)]}_{\text{MODEL error}}$$

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Formal definition of SUPERVISED LEARNING

"LEARNING = APPROXIMATE + GENERALIZE"

Given a FINITE set of examples $(\mathbf{x}_1, y_1), (\mathbf{x}_2, y_2), \dots, (\mathbf{x}_n, y_n)$

where $\mathbf{x}_i \in \mathbb{R}^d$ = input vectors, and $y_i \in \mathbb{R}^s$ = target values

(given by the "teacher"), find a function h which

"approximates AND GENERALIZES as best as possible"

the underlying function such that $y_i = f(\mathbf{x}_i) + \text{noise}$

\Rightarrow goal = to minimize the GENERALIZATION error

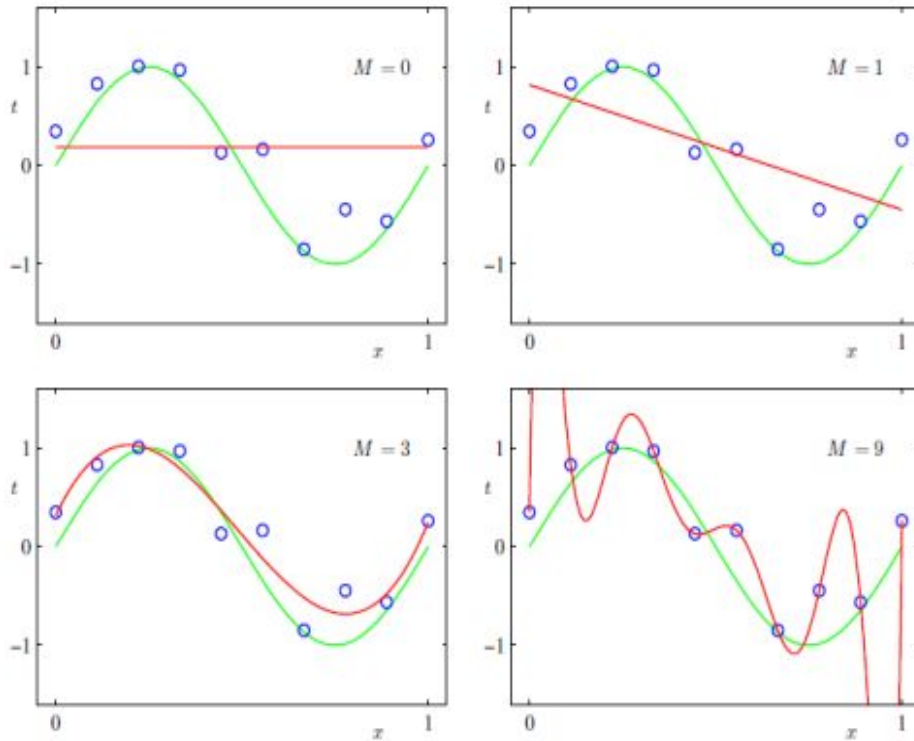
$$E_{\text{gen}} = \int \|h(\mathbf{x}) - f(\mathbf{x})\|^2 p(\mathbf{x}) d\mathbf{x}$$

(where $p(\mathbf{x})$ = probability distribution of \mathbf{x})

About over-fitting

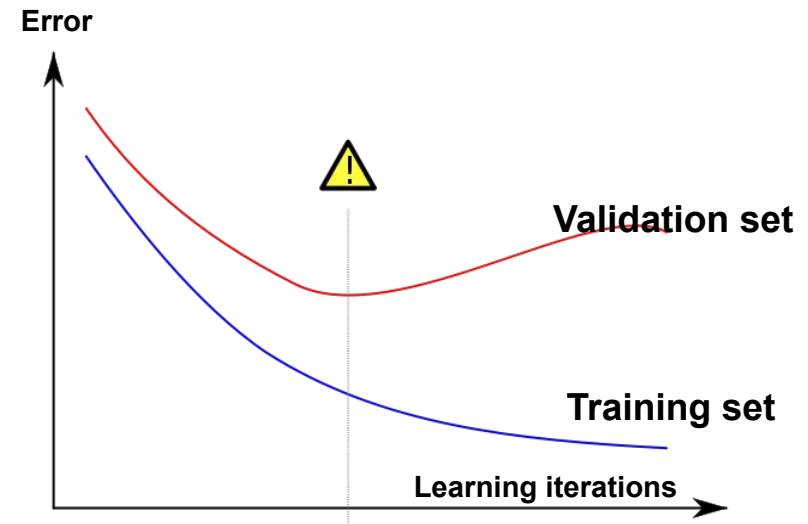
The generalization error cannot be directly measured, only empirical error on examples can be estimated:

$$\mathbb{E}_{\text{emp}} = \left(\sum_i \|h(\mathbf{x}_i) - \mathbf{y}_i\|^2 \right) / n$$



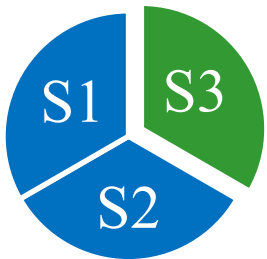
Fitting a data set to different orders of polynomials
[from Bishop, "Pattern Recognition and Machine Learning"]

Detection of over-fitting for an iterative algorithm



To **avoid over-fitting** and **maximize generalization**, absolutely essential to use some **VALIDATION estimation**, for optimizing training hyper-parameters (and stopping criterion):

- either use a *separate validation dataset* (random split of data into Training-set + Validation-set)
- or use **CROSS-VALIDATION**:
 - Repeat k times: train on $(k-1)/k$ proportion of data + estimate error on remaining $1/k$ portion
 - Average the k error estimations



3-fold cross-validation:

- Train on $S1 \cup S2$ then estimate err_{S3} error on $S3$
- Train on $S1 \cup S3$ then estimate err_{S2} error on $S2$
- Train on $S2 \cup S3$ then estimate err_{S1} error on $S1$
- Average validation error: $(\text{err}_{S1} + \text{err}_{S2} + \text{err}_{S3})/3$

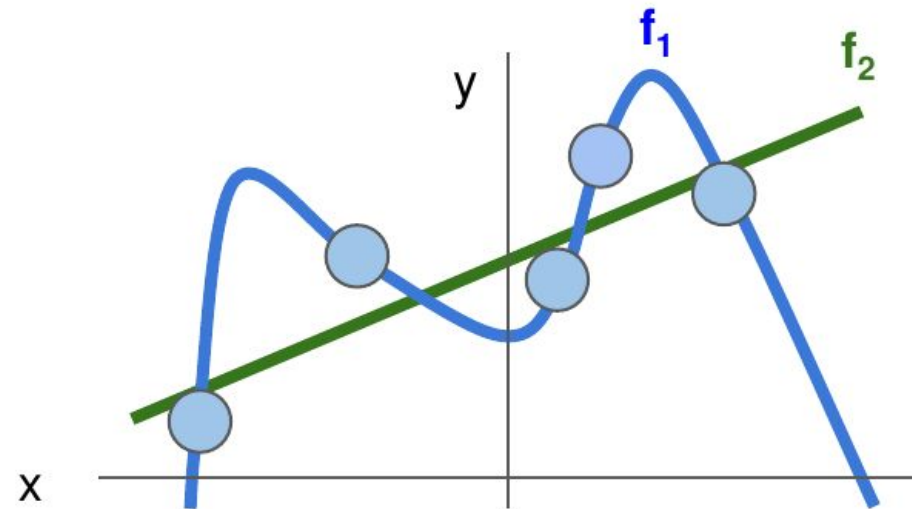
Regularization

Want to find:

- “Simplest” h
- Often, add term to loss
- Consider:
 - Loss L
 - Weights W
 - Function f

$$L(W) = \frac{1}{N} \sum_{i=1}^N L_i(f(x_i, W), y_i)$$

Data loss: Model predictions should match training data



From: Lecture 3: Regularization and Optimization, Fei-Fei Li, Ehsan Adeli, Zane Durante

Regularization

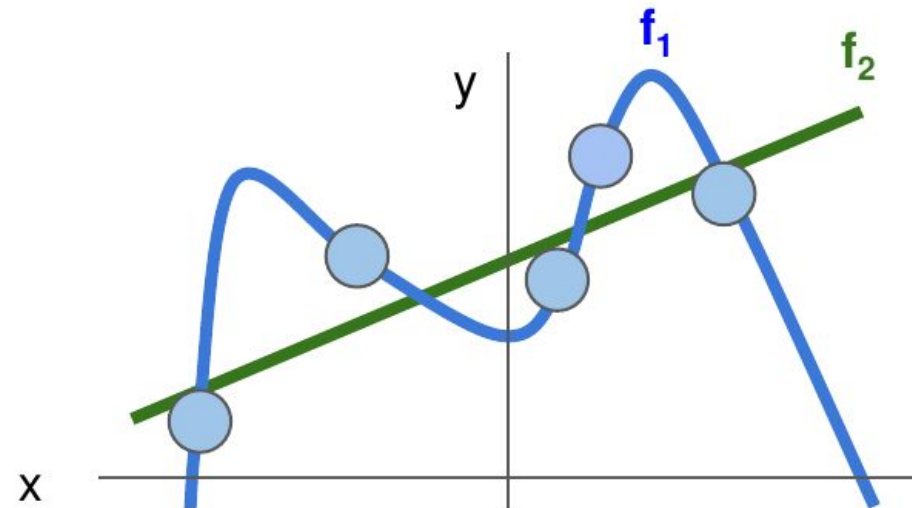
Want to find:

- “Simplest” h
- Often, add term to loss
- Consider:
 - Loss L
 - Weights W
 - Function f
 - Regularization R

$$L(W) = \underbrace{\frac{1}{N} \sum_{i=1}^N L_i(f(x_i, W), y_i)}_{\text{Data loss}} + \underbrace{\lambda R(W)}_{\text{Regularization}}$$

Data loss: Model predictions should match training data

Regularization: Prevent the model from doing *too well* on training data



Want to find:

- “Simplest” h
- Often, add term to loss
- Consider:
 - Loss L
 - Weights W
 - Function f
 - Regularization R

Simple examples

L2 regularization: $R(W) = \sum_k \sum_l W_{k,l}^2$

L1 regularization: $R(W) = \sum_k \sum_l |W_{k,l}|$

Elastic net (L1 + L2): $R(W) = \sum_k \sum_l \beta W_{k,l}^2 + |W_{k,l}|$

$$L(W) = \underbrace{\frac{1}{N} \sum_{i=1}^N L_i(f(x_i, W), y_i)}_{\text{Data loss}} + \underbrace{\lambda R(W)}_{\text{Regularization}}$$

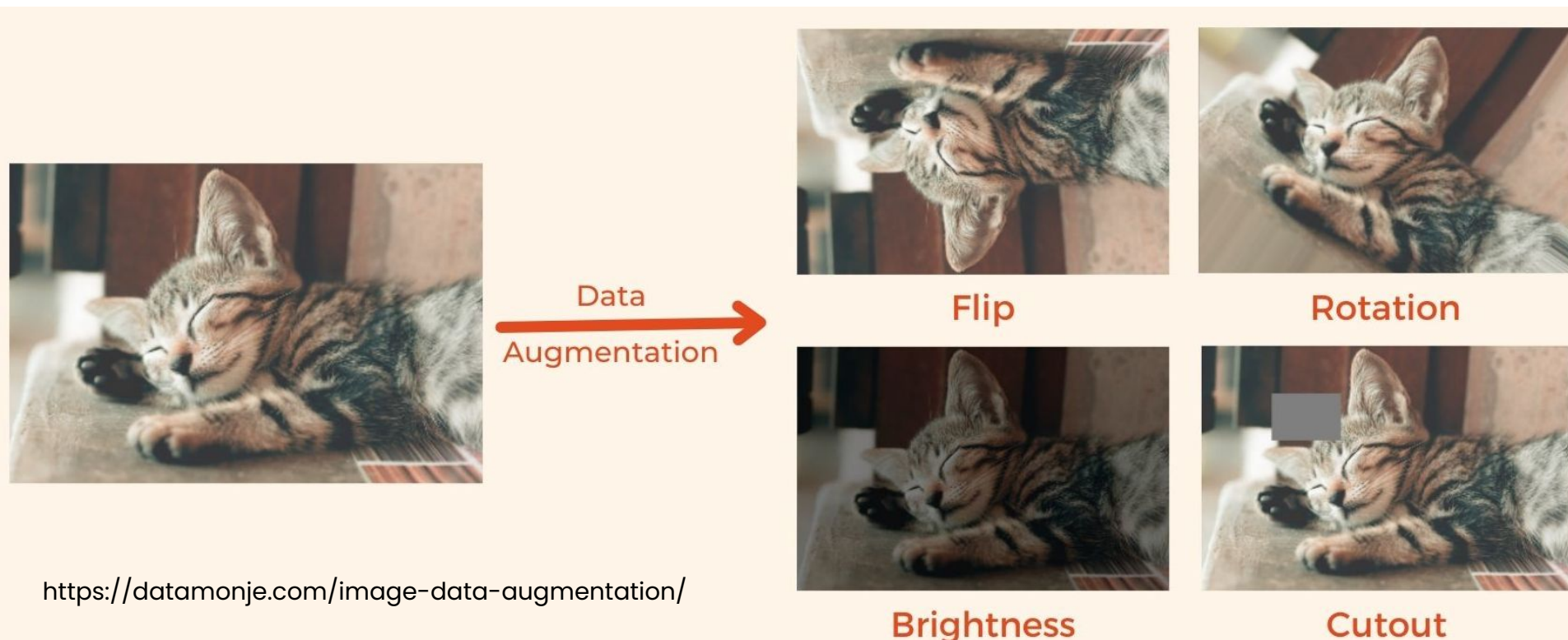
Data loss: Model predictions should match training data

Regularization: Prevent the model from doing *too* well on training data

Data augmentation (for classification)

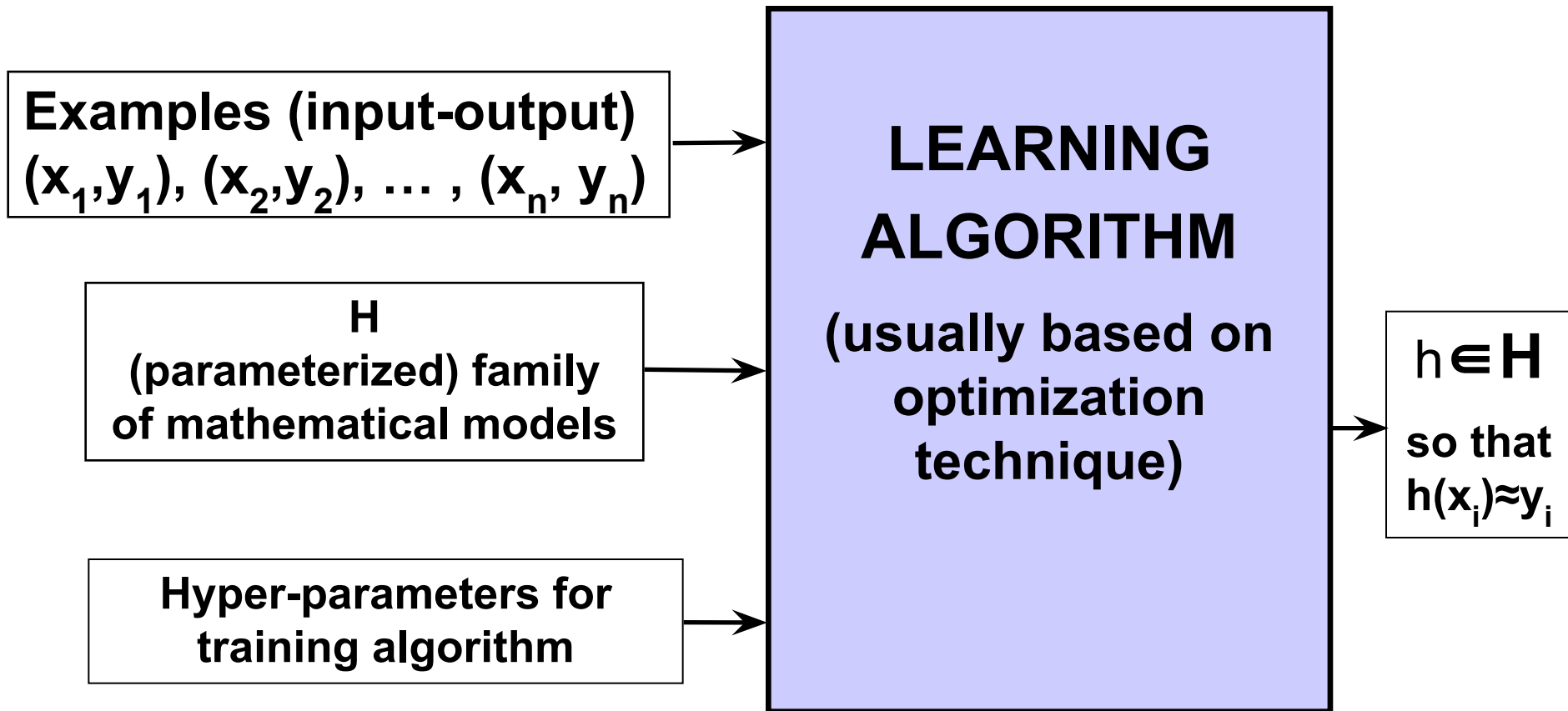
In the case of CLASSIFICATION, over-fitting avoidance and better generalization can also be favored by DATA AUGMENTATION:

for each labelled example in training set, generate several slightly *distorted* variants which shall have the same label



Synthesis on various algorithms for SUPERVISED Machine-Learning

Supervised learning



Typology of classification methods

- By *similarity* □ Nearest Neighbors (kNN)
- By *succession of elementary tests* □ Decision Trees
- By *probabilistic computations* (using hypothesis on distribution of classes) □ Bayesian methods
- By *error minimization* (gradient descent, etc...) □ Neural Networks, etc...
Idem + "*margin*" maximization □ Support Vector Machines (SVM)
- By *voting committee (ensemble methods)*:
 - using trees □ Random Forests
 - using successive weightings of examples □ Boosting

Summary of main shallow SUPERVISED learning algorithms

- **Decision trees**: naturally adapted to symbolic inputs, very fast, good scaling for very high number of classes, "white" box;
BUT *noise sensitive*
- **Multi-layer neural networks**: *universal approximators*, good generalization, *easy handling of multi-class*;
BUT optimum model NOT guaranteed, many critical hyper-parameters (# hidden neurons, weight init., learning rate, # training epochs,...)
- **Support Vector Machines**: maths-guaranteed optimal separation, possible handling of *structured input* (graphs, etc...) via kernel;
BUT not very efficient for multi-class (K times 1-vs-all SVMs, or at least $\log(K)$ times Ci-vs-Cj), training computation rises quickly with input dim and # of examples $O(\max(N, D) * \min(N, D)^2)$
- **Boosting** of « weak » classifiers: simple algo, *can build strong classifier from any weak classifier*, *can select features during training*;
BUT not very efficient for multi-class (n times 1-vs-all)
- **Random forests**: *OK for symbolic input*, robustness to noise, very fast to compute, *efficient for large # of classes and high input dim*;
BUT *training sometimes long*

Model type choice criteria for SUPERVISED learning

	MLP Neural Network	ConvNets	SVM	Boosting	Decision Tree	Random Forest
Many classes	+	+	--	--		++
High dimension of input			-		+	++
Many examples		REQUIRED (except if transfer-learn- ing)	-			
Interpretability (« white » box)	-	--			YES	
Data OTHER than vectors of values		Only “grid” data	Structured (string, graph)		symbolic	symbolic
Robustness to noise and erroneous labels	+	+	++		--	++
Ease/speed of training	-	---	+		++	+
Handling of features		Learn them		Automated selection		
Execution time		-			+++	+

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